

Search Notes	Application/Control No.	Applicant(s)/Patent Under Reexamination
	10075051	WANG ET AL.
	Examiner	Art Unit
	DJENANE M BAYARD	2444

SEARCHED

Class	Subclass	Date	Examiner
709	217, 218, 219, 226, 229	6/01/09	db

SEARCH NOTES

Search Notes	Date	Examiner
East	6/01/09	db
Double Patenting	6/01/09	db

INTERFERENCE SEARCH

Class	Subclass	Date	Examiner
709	217, 218, 219, 226, 229	6/01/09	db

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